

MOS FIELD EFFECT TRANSISTOR 2SK4075

(TO-252)

SWITCHING N-CHANNEL POWER MOS FET

DESCRIPTION

The 2SK4075 is N-channel MOS FET designed for high current switching applications.

ORDERING INFORMATION

PART NUMBER	LEAD PLATING	PACKING	PACKAGE
2SK4075-ZK-E1-AY	Pure Sn (Tin)	Таре	TO-252 (MP-3ZK)
2SK4075-ZK-E2-AY		2500 p/reel	typ. 0.27 g

FEATURES

• Low on-state resistance

 $R_{DS(on)1} = 6.7 \text{ m}\Omega \text{ MAX.} \text{ (V}_{GS} = 10 \text{ V}, I_{D} = 30 \text{ A})$

 $R_{DS(on)2} = 10 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 4.5 \text{ V, Ip} = 15 \text{ A)}$

• Low Ciss: Ciss = 2900 pF TYP.

· Logic level drive type

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	40	V
Gate to Source Voltage (V _{DS} = 0 V)	Vgss	±20	V
Drain Current (DC) (Tc = 25°C)	I _{D(DC)}	±60	Α
Drain Current (pulse) Note1	ID(pulse)	±180	Α
Total Power Dissipation (Tc = 25°C)	P _{T1}	52	W
Total Power Dissipation (T _A = 25°C)	P _{T2}	1.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	T _{stg}	-55 to +150	°C
Single Avalanche Current Note2	las	28	Α
Single Avalanche Energy Note2	Eas	78	mJ

Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1%

2. Starting T_{ch} = 25°C, V_{DD} = 20 V, R_G = 25 Ω , V_{GS} = 20 \rightarrow 0 V, L = 100 μ H

THERMAL RESISTANCE

Channel to Case Thermal Resistance $R_{th(ch-C)}$ 2.4 °C/W Channel to Ambient Thermal Resistance $R_{th(ch-A)}$ 125 °C/W

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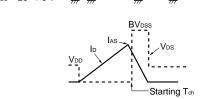
ELECTRICAL CHARACTERISTICS (TA = 25°C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = 40 V, V _{GS} = 0 V			1	μА
Gate Leakage Current	Igss	V _{GS} = ±20 V, V _{DS} = 0 V			±100	nA
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1 mA	1.5	2.0	2.5	V
Forward Transfer Admittance Note	yfs	V _{DS} = 10 V, I _D = 15 A	9.3			S
Drain to Source On-state Resistance Note	RDS(on)1	V _{GS} = 10 V, I _D = 30 A		5.2	6.7	mΩ
	RDS(on)2	V _{GS} = 4.5 V, I _D = 15 A		7.2	10	mΩ
Input Capacitance	Ciss	V _{DS} = 10 V		2900		pF
Output Capacitance	Coss	V _{GS} = 0 V		450		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		293		pF
Turn-on Delay Time	t _{d(on)}	V _{DD} = 20 V		18		ns
Rise Time	tr	ID = 30 A		16		ns
Turn-off Delay Time	t _{d(off)}	V _{GS} = 10 V		54		ns
Fall Time	t f	R _G = 0 Ω		9		ns
Total Gate Charge	Q _G	V _{DD} = 32 V		54		nC
Gate to Source Charge	Qgs	V _{GS} = 10 V		11		nC
Gate to Drain Charge	Q _{GD}	ID = 60 A		15		nC
Body Diode Forward Voltage Note	V _{F(S-D)}	I _F = 60 A, V _{GS} = 0 V		0.9	1.5	V
Reverse Recovery Time	trr	IF = 60 A, VGS = 0 V		33		ns
Reverse Recovery Charge	Qrr	di/dt = 100 A/ <i>μ</i> s		33		nC

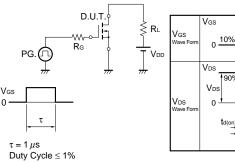
Note Pulsed

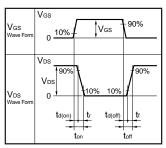
TEST CIRCUIT 1 AVALANCHE CAPABILITY

$R_{G} = 25 \Omega \downarrow I$ $R_{G} = 25 \Omega \downarrow I$ V_{DD} $V_{DS} = 20 \rightarrow 0 V$



TEST CIRCUIT 2 SWITCHING TIME



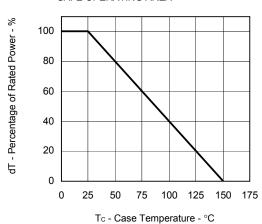


TEST CIRCUIT 3 GATE CHARGE

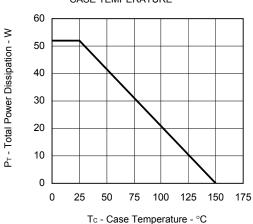
$$\begin{array}{c|c} D.U.T. \\ \hline \\ IG = 2 \text{ mA} \\ \hline \\ VOD \\ \hline \end{array}$$

TYPICAL CHARACTERISTICS (TA = 25°C)

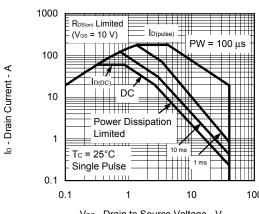
DERATING FACTOR OF FORWARD BIAS SAFE OPERATING AREA

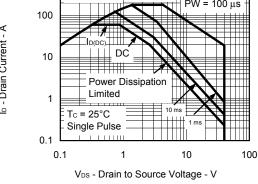


TOTAL POWER DISSIPATION vs. CASE TEMPERATURE

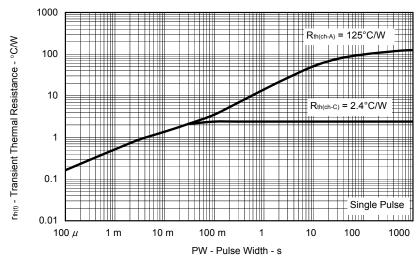


FORWARD BIAS SAFE OPERATING AREA

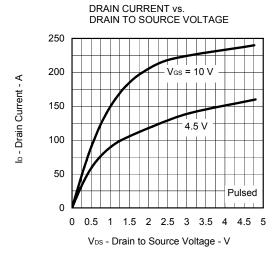


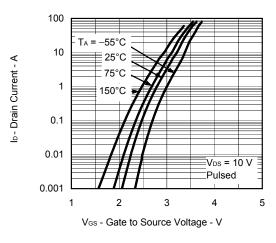


TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH

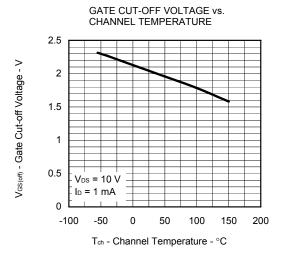


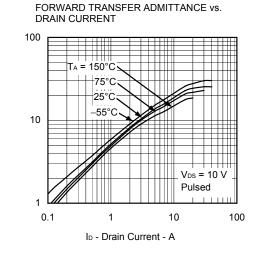
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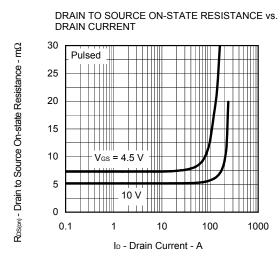


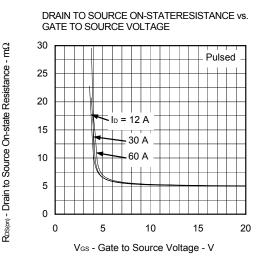


FORWARD TRANSFER CHARACTERISTICS





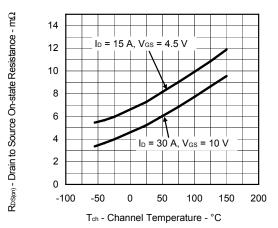




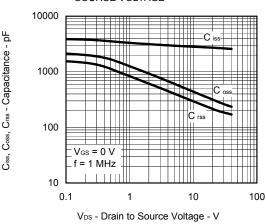
4

| y_{fs} | - Forward Transfer Admittance - S

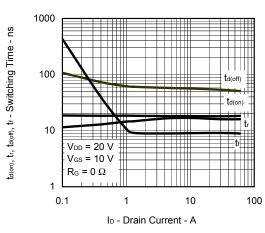
DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



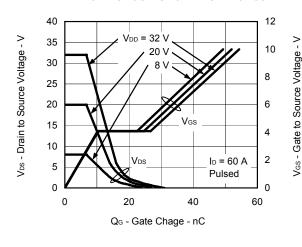
CAPACITANCE vs. DRAIN TO SOURCE VOLTAGE



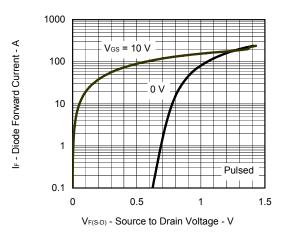
SWITCHING CHARACTERISTICS



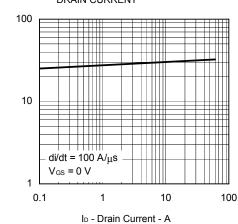
DYNAMIC INPUT/OUTPUT CHARACTERISTICS



SOURCE TO DRAIN DIODE FORWARD VOLTAGE



REVERSE RECOVERY TIME vs. DRAIN CURRENT

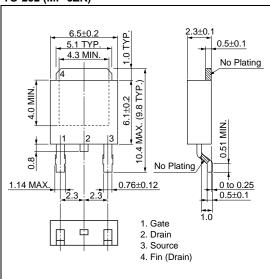


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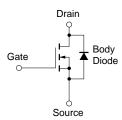
trr - Reverse Recovery Time - ns

PACKAGE DRAWING (Unit: mm)

TO-252 (MP-3ZK)



EQUIVALENT CIRCUIT



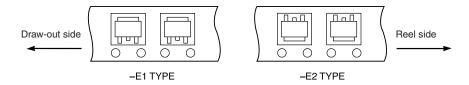
Remark The diode connected between the gate and source of the transistor serves as a protector against ESD.

When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

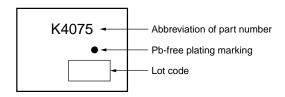


TAPE INFORMATION

There are two types (-E1, -E2) of taping depending on the direction of the device.



MARKING INFORMATION



RECOMMENDED SOLDERING CONDITIONS

The 2SK4075 should be soldered and mounted under the following recommended conditions.

For soldering methods and conditions other than those recommended below, please contact an NEC Electronics sales representative.

For technical information, see the following website.

Semiconductor Device Mount Manual (http://www.necel.com/pkg/en/mount/index.html)

Soldering Method	Soldering Conditions	Recommended Condition Symbol
Infrared reflow	Maximum temperature (Package's surface temperature): 260°C or below	IR60-00-3
	Time at maximum temperature: 10 seconds or less	
	Time of temperature higher than 220°C: 60 seconds or less	
	Preheating time at 160 to 180°C: 60 to 120 seconds	
	Maximum number of reflow processes: 3 times	
	Maximum chlorine content of rosin flux (percentage mass): 0.2% or less	
Partial heating	Maximum temperature (Pin temperature): 350°C or below	P350
	Time (per side of the device): 3 seconds or less	
	Maximum chlorine content of rosin flux: 0.2% (wt.) or less	

Caution Do not use different soldering methods together (except for partial heating).

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